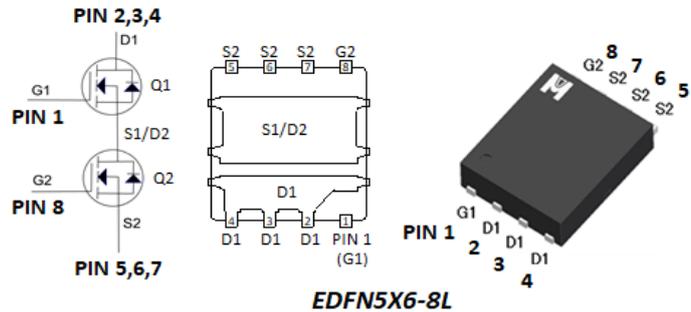


**Dual N-Channel Logic Level Enhancement Mode Field Effect Transistor**

**•Product Summary:**

	Q1	Q2
$BV_{DSS}$	30V	30V
$R_{DSON (MAX.) @ V_{GS}=10V}$	5.3mΩ	2.0mΩ
$R_{DSON (MAX.) @ V_{GS}=4.5V}$	8.8mΩ	2.8mΩ
$I_D @ T_C=25^{\circ}C$	79A	199A
$I_D @ T_A=25^{\circ}C$	16A	29A

**• Pin Description:**



Dual N Channel MOSFET  
UIS, Rg 100% Tested  
RoHS & Halogen Free & TSCA Compliant



**•ABSOLUTE MAXIMUM RATINGS ( $T_C = 25^{\circ}C$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS		UNIT	
		Q1	Q2		
Gate-Source Voltage	$V_{GS}$	±20	±12	V	
Continuous Drain Current	$I_D$	$T_C = 25^{\circ}C$	79	199	A
		$T_C = 100^{\circ}C$	50	126	
Continuous Drain Current	$I_D$	$T_A = 25^{\circ}C$	16	29	
		$T_A = 70^{\circ}C$	13	23	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	141	384		
Avalanche Current	$I_{AS}$	74	100		
Avalanche Energy	L = 0.01mH	EAS	27.4	50	mJ
Repetitive Avalanche Energy <sup>2</sup>	L = 0.05mH	EAR	137	250	
Power Dissipation	$P_D$	$T_C = 25^{\circ}C$	54	125	W
		$T_C = 100^{\circ}C$	22	50	
Power Dissipation	$P_D$	$T_A = 25^{\circ}C$	2.4	2.7	W
		$T_A = 70^{\circ}C$	1.5	1.7	
Operating Junction & Storage Temperature Range	$T_j, T_{stg}$	-55 to 150		°C	

• 100% UIS testing in condition of  $V_D=25V, L=0.01mH, V_G=10V, I_L=54A, R_G=25\Omega$ , Rated  $V_{DS}=30V$  N-CH\_Q1

• 100% UIS testing in condition of  $V_D=25V, L=0.01mH, V_G=10V, I_L=70A, R_G=25\Omega$ , Rated  $V_{DS}=30V$  N-CH\_Q2

**•THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM		UNIT
			Q1	Q2	
Junction-to-Case	$R_{\theta JC}$		2.3	1.0	°C/W
Junction-to-Top	Steady-State	$R_{\theta JT}$	42	30	
			$t \leq 10s$	23	
Junction-to-Ambient <sup>3</sup>	Steady-State	$R_{\theta JA}$	53	46	

<sup>1</sup>Pulse width limited by maximum junction temperature.

<sup>2</sup>Duty cycle < 1%

<sup>3</sup>The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^{\circ}C$ .

<sup>4</sup>Guarantee by Engineering test



▪ Q1\_ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage <sup>4</sup>	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	30			V
Gate Threshold Voltage <sup>4</sup>	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.3	1.6	2.2	
Gate-Body Leakage <sup>4</sup>	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V			±100	nA
Zero Gate Voltage Drain Current <sup>4</sup>	I <sub>DSS</sub>	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V			1	μA
		V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125 °C			25	
On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V	79			A
Drain-Source On-State Resistance <sup>1,4</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A		4.1	5.3	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 20A		6.0	8.8	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 15A		50		S
<b>DYNAMIC</b>						
Input Capacitance <sup>5</sup>	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz		830		pF
Output Capacitance <sup>5</sup>	C <sub>oss</sub>			330		
Reverse Transfer Capacitance <sup>5</sup>	C <sub>rss</sub>			40		
Gate Resistance <sup>4,5</sup>	R <sub>g</sub>	f = 1MHz		0.7		Ω
Total Gate Charge <sup>1,2,5</sup>	Q <sub>g</sub> (V <sub>GS</sub> =10V)	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A		15		nC
	Q <sub>g</sub> (V <sub>GS</sub> =4.5V)			6.9		
Gate-Source Charge <sup>1,2,5</sup>	Q <sub>gs</sub>			3.3		
Gate-Drain Charge <sup>1,2,5</sup>	Q <sub>gd</sub>			1.8		
Turn-On Delay Time <sup>1,2,5</sup>	t <sub>d(on)</sub>			5.8		
Rise Time <sup>1,2,5</sup>	t <sub>r</sub>	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 5A, R <sub>g</sub> = 3Ω		11		
Turn-Off Delay Time <sup>1,2,5</sup>	t <sub>d(off)</sub>			14		
Fall Time <sup>1,2,5</sup>	t <sub>f</sub>			3.1		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS</b>						
Continuous Current	I <sub>S</sub>				45	A
Pulsed Current <sup>3</sup>	I <sub>SM</sub>				141	
Forward Voltage <sup>1,4</sup>	V <sub>SD</sub>	I <sub>F</sub> = 20A, V <sub>GS</sub> = 0V			1.2	V
Reverse Recovery Time <sup>5</sup>	t <sub>rr</sub>	I <sub>F</sub> = 20A, dI <sub>F</sub> /dt = 400A / μS		12		nS
Peak Reverse Recovery Current <sup>5</sup>	I <sub>RM(REC)</sub>			2.1		A
Reverse Recovery Charge <sup>5</sup>	Q <sub>rr</sub>				13	

<sup>1</sup>Pulse test : Pulse Width ≤ 300 usec, Duty Cycle ≤ 2%.

<sup>2</sup>Independent of operating temperature.

<sup>3</sup>Pulse width limited by maximum junction temperature.

<sup>4</sup>Guarantee by FT test Item

<sup>5</sup>Guarantee by Engineering test

EMC will review datasheet by quarter, and update new version.



•Q1\_TYPICAL CHARACTERISTICS

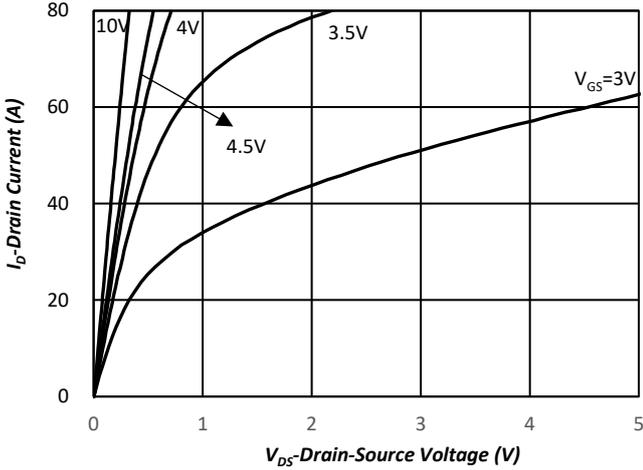


Fig.1 Typical Output Characteristics

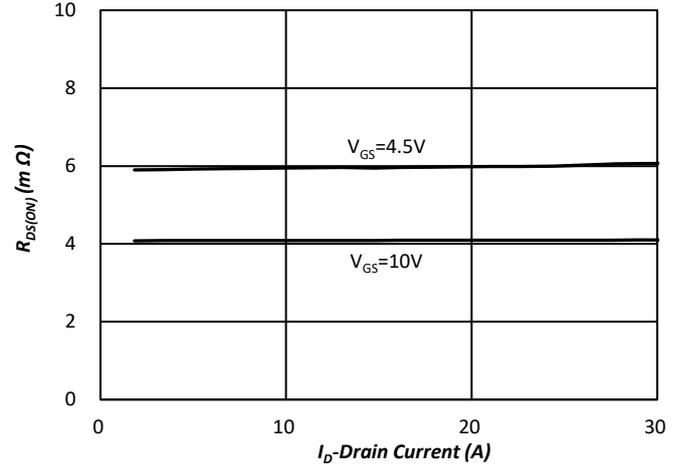


Fig.2 On-Resistance Variation with Drain Current and Gate Voltage

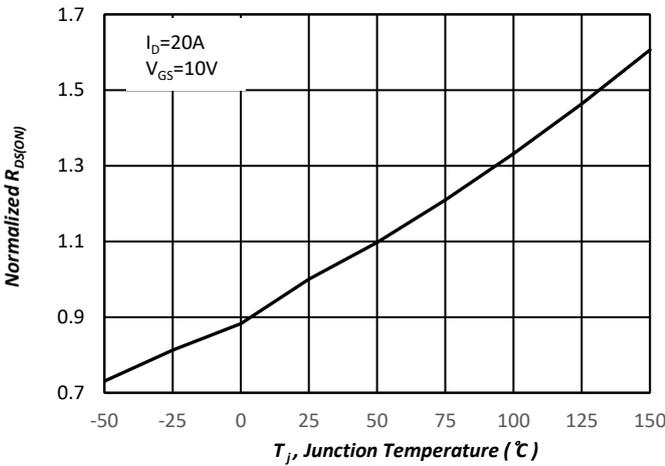


Fig.3 Normalized On-Resistance v.s. Junction Temperature

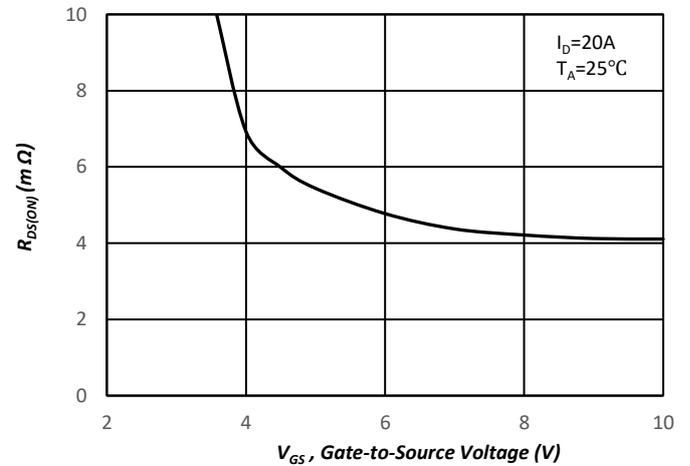


Fig.4 On-Resistance v.s. Gate Voltage

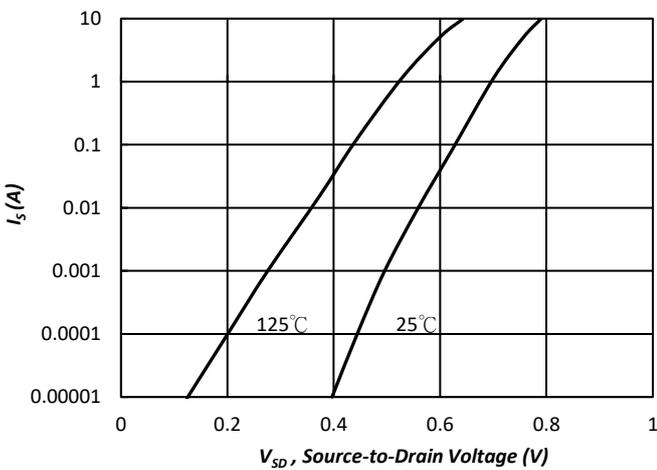


Fig.5 Forward Characteristic of Reverse Diode

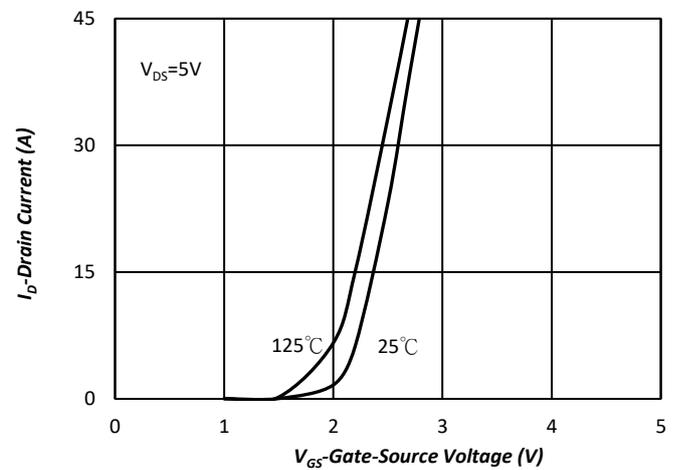


Fig.6 Transfer Characteristics

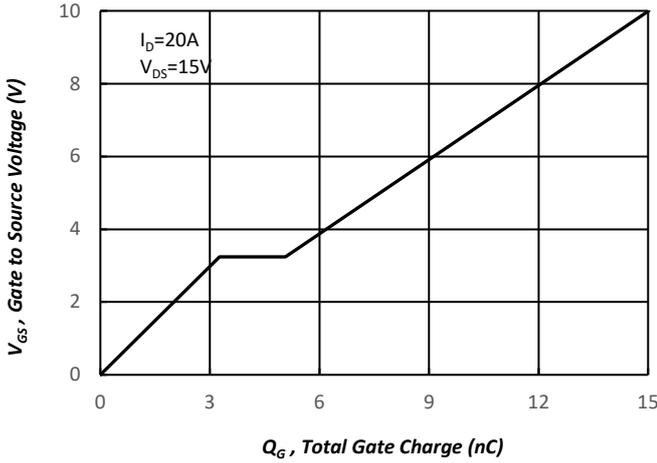


Fig.7 Gate Charge Characteristics

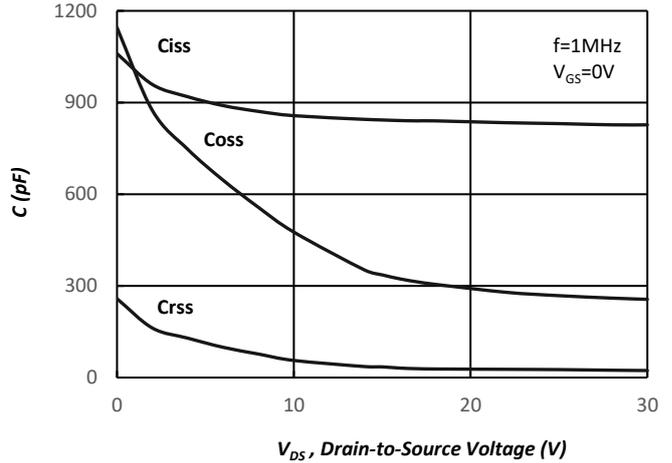


Fig.8 Typical Capacitance Characteristics

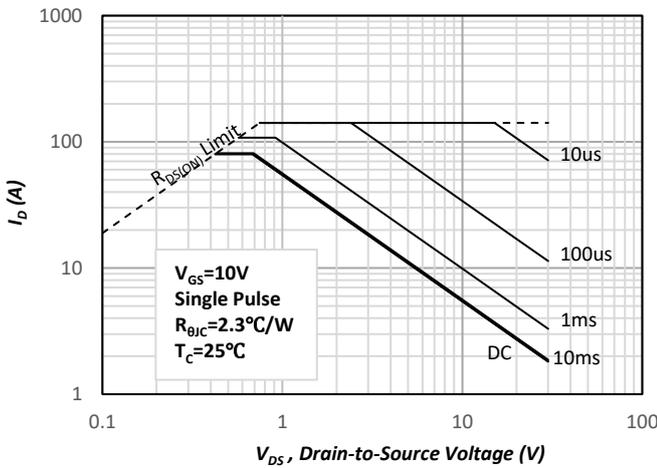


Fig.9. Maximum Safe Operating Area

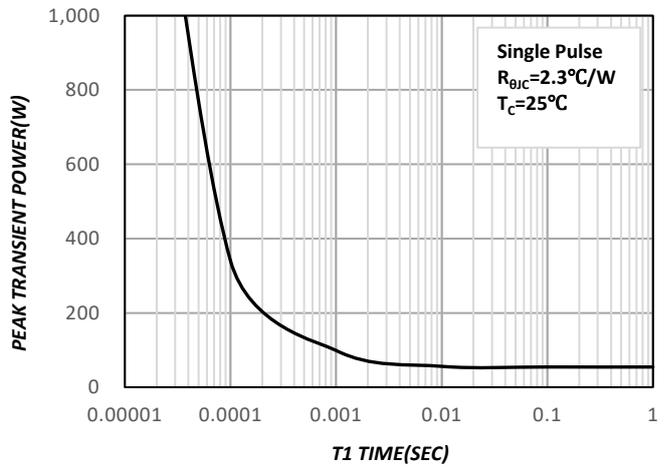


Fig.10. Single Pulse Maximum Power Dissipation

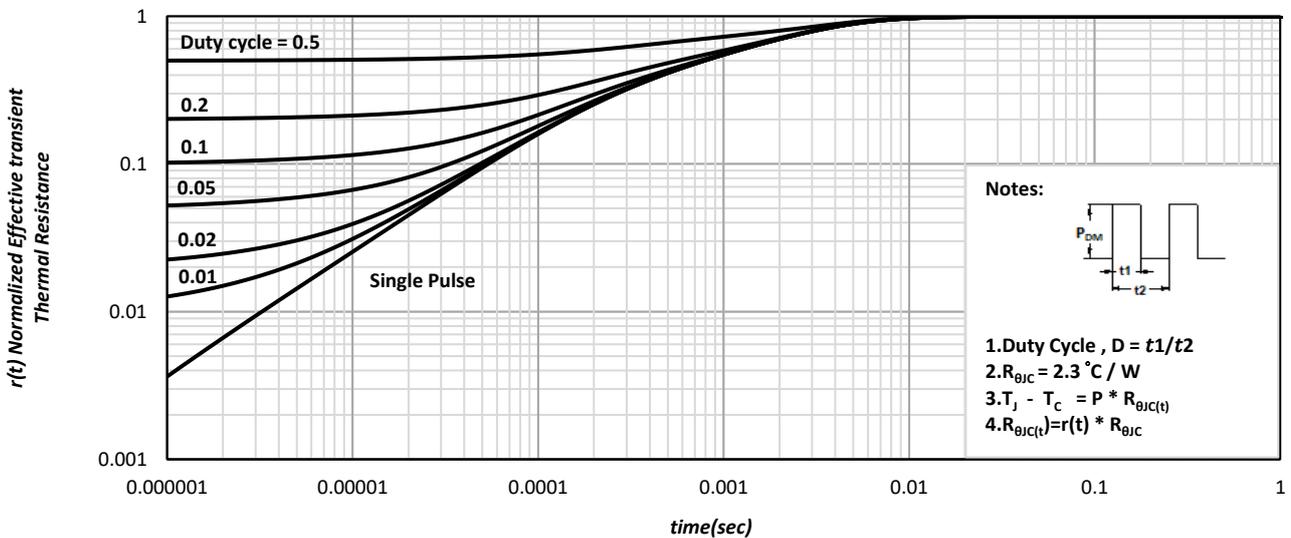


Fig.11. Effective Transient Thermal Impedance



▪ Q2\_ELECTRICAL CHARACTERISTICS (T<sub>J</sub> = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage <sup>4</sup>	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	30			V
Gate Threshold Voltage <sup>4</sup>	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	1.3	1.6	2.2	
Gate-Body Leakage <sup>4</sup>	I <sub>GSS</sub>	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±12V			±100	nA
Zero Gate Voltage Drain Current <sup>4</sup>	I <sub>DSS</sub>	V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V			1	μA
		V <sub>DS</sub> = 30V, V <sub>GS</sub> = 0V, T <sub>J</sub> = 125 °C			25	
On-State Drain Current <sup>1</sup>	I <sub>D(ON)</sub>	V <sub>DS</sub> = 10V, V <sub>GS</sub> = 10V	199			A
Drain-Source On-State Resistance <sup>1,4</sup>	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A		1.5	2.0	mΩ
		V <sub>GS</sub> = 4.5V, I <sub>D</sub> = 20A		2.1	2.8	
Forward Transconductance <sup>1</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 5V, I <sub>D</sub> = 15A		110		S
<b>DYNAMIC</b>						
Input Capacitance <sup>5</sup>	C <sub>iss</sub>	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 15V, f = 1MHz		2470		pF
Output Capacitance <sup>5</sup>	C <sub>oss</sub>			1150		
Reverse Transfer Capacitance <sup>5</sup>	C <sub>rss</sub>			55		
Gate Resistance <sup>4,5</sup>	R <sub>g</sub>	f = 1MHz		0.8		Ω
Total Gate Charge <sup>1,2,5</sup>	Q <sub>g</sub> (V <sub>GS</sub> =10V)	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A		45		nC
	Q <sub>g</sub> (V <sub>GS</sub> =4.5V)			20		
Gate-Source Charge <sup>1,2,5</sup>	Q <sub>gs</sub>			8.2		
Gate-Drain Charge <sup>1,2,5</sup>	Q <sub>gd</sub>			4.1		
Turn-On Delay Time <sup>1,2,5</sup>	t <sub>d(on)</sub>			9.9		
Rise Time <sup>1,2,5</sup>	t <sub>r</sub>	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 10V, I <sub>D</sub> = 5A, R <sub>g</sub> = 3Ω		13		nS
Turn-Off Delay Time <sup>1,2,5</sup>	t <sub>d(off)</sub>			33		
Fall Time <sup>1,2,5</sup>	t <sub>f</sub>			8.2		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS</b>						
Continuous Current	I <sub>S</sub>				104	A
Pulsed Current <sup>3</sup>	I <sub>SM</sub>				384	
Forward Voltage <sup>1,4</sup>	V <sub>SD</sub>	I <sub>F</sub> = 20A, V <sub>GS</sub> = 0V			1.2	V
Reverse Recovery Time <sup>5</sup>	t <sub>rr</sub>	I <sub>F</sub> = 20A, dI <sub>F</sub> /dt = 400A /μS		29		nS
Peak Reverse Recovery Current <sup>5</sup>	I <sub>RM(REC)</sub>			3.3		A
Reverse Recovery Charge <sup>5</sup>	Q <sub>rr</sub>			47		nC

<sup>1</sup>Pulse test : Pulse Width ≤ 300 usec, Duty Cycle ≤ 2%.

<sup>2</sup>Independent of operating temperature.

<sup>3</sup>Pulse width limited by maximum junction temperature.

<sup>4</sup>Guarantee by FT test Item

<sup>5</sup>Guarantee by Engineering test

EMC will review datasheet by quarter, and update new version.



-Q2\_TYPICAL CHARACTERISTICS

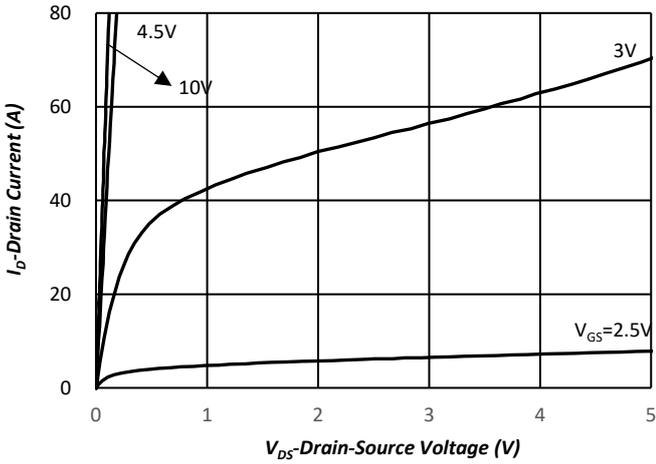


Fig.1 Typical Output Characteristics

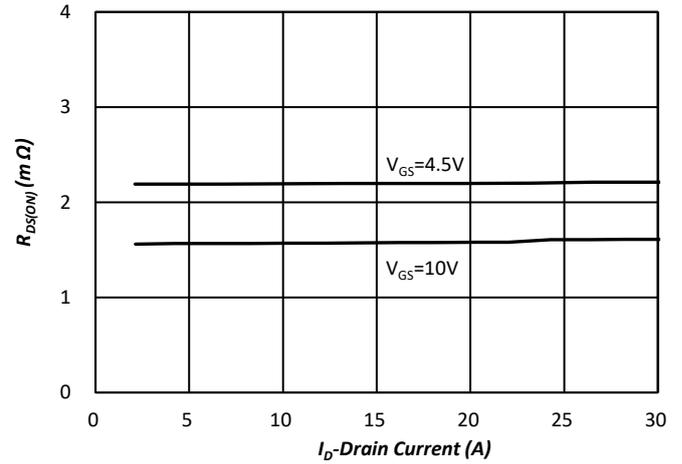


Fig.2 On-Resistance Variation with Drain Current and Gate Voltage

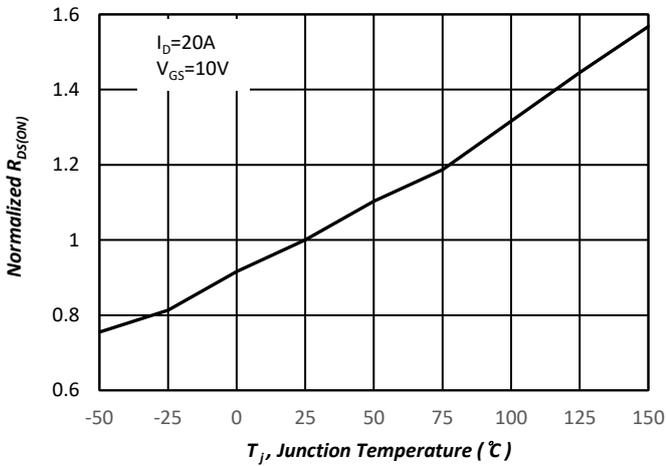


Fig.3 Normalized On-Resistance v.s. Junction Temperature

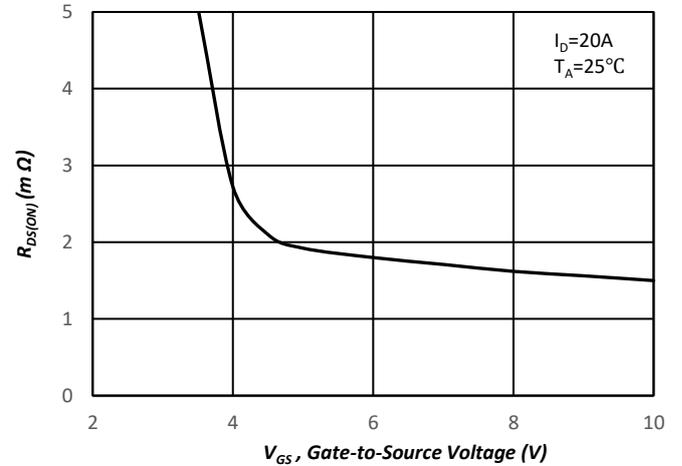


Fig.4 On-Resistance v.s. Gate Voltage

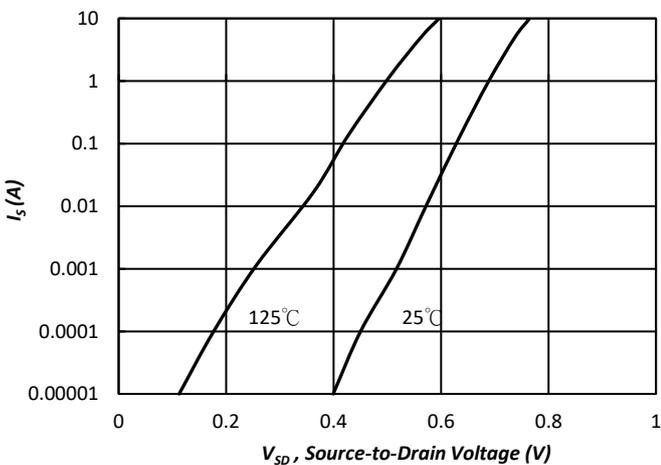


Fig.5 Forward Characteristic of Reverse Diode

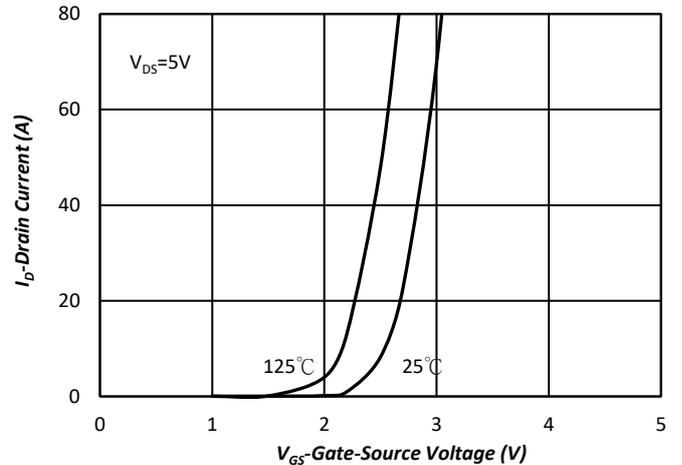
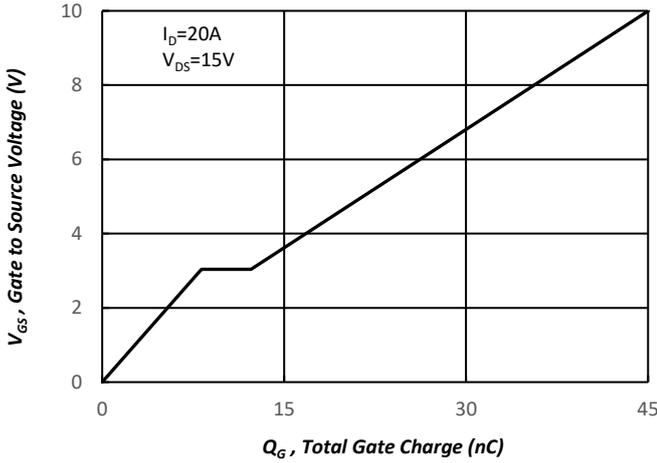
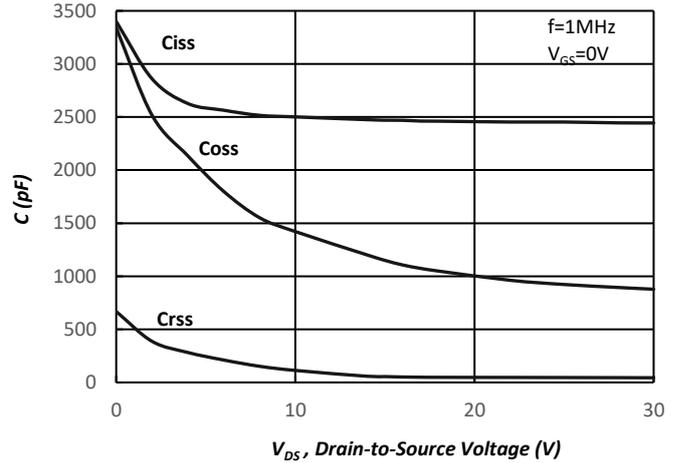


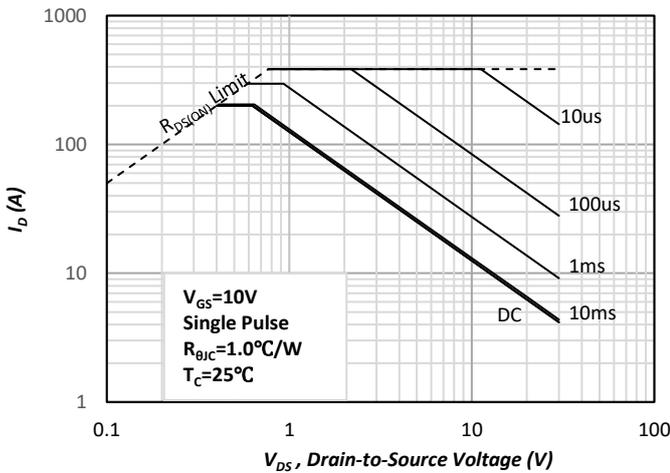
Fig.6 Transfer Characteristics



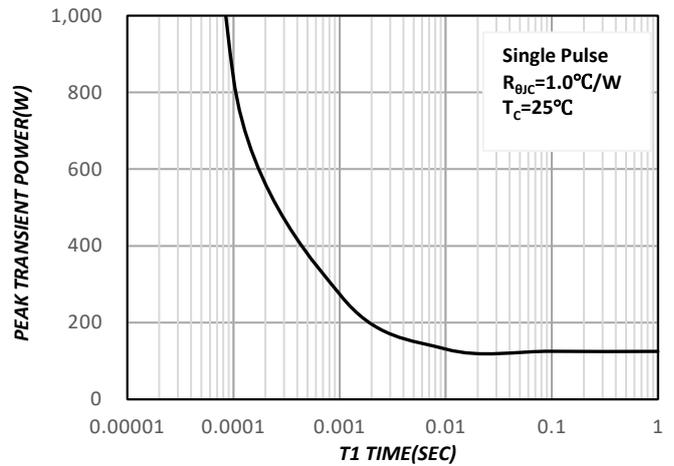
**Fig.7 Gate Charge Characteristics**



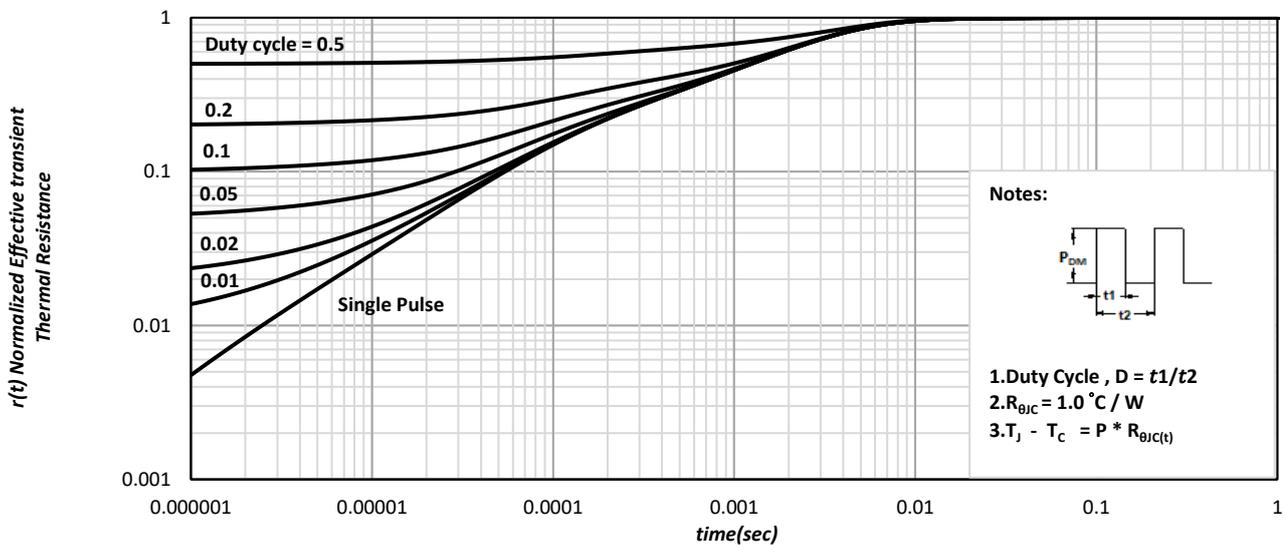
**Fig.8 Typical Capacitance Characteristics**



**Fig.9. Maximum Safe Operating Area**



**Fig.10. Single Pulse Maximum Power Dissipation**



**Fig.11. Effective Transient Thermal Impedance**

**Ordering & Marking Information:**

Device Name: EMB02K03HPCS for Asymmetric EDFN5X6-8L



B02K03S: Device Name

ABCDEFG: Date Code

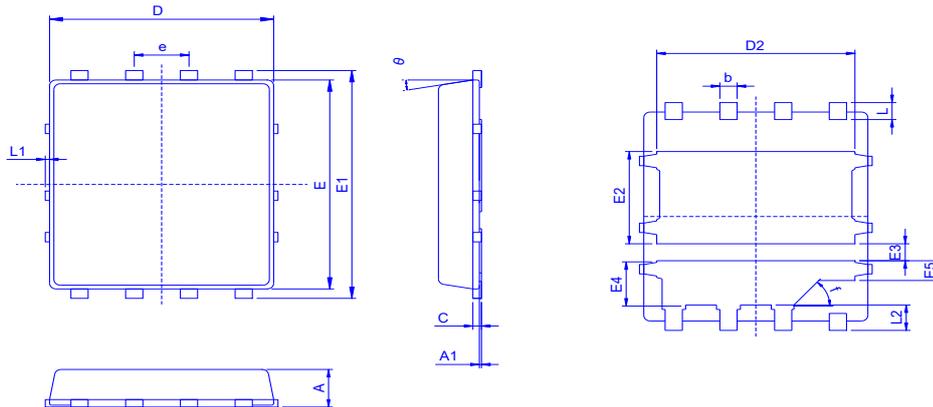
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B: Year(A:2008 B:2009 C:2010....)

C: Month(A:01 B:02 C:03 D:04 E:05 F:06 G:07 H:08 I:09 J:10 K:11 L:12)

DEFG: Serial No.

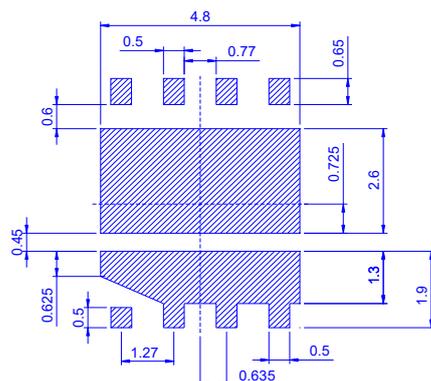
**Outline Drawing**



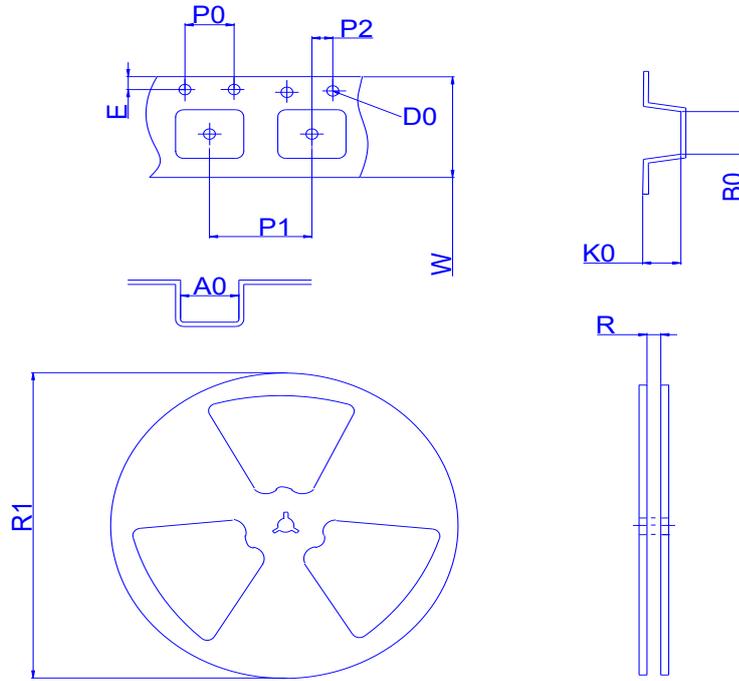
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Min.	0.85	-	0.33	0.15	4.80	3.61	5.55	5.90	2.02	0.40	1.10	0.48	-
Typ.	0.95	-	0.40	0.20	4.90	3.81	5.65	6.00	2.17	0.45	1.18	0.53	1.27
Max.	1.05	0.05	0.46	0.30	5.00	4.70	5.80	6.10	2.50	0.60	1.42	0.58	-

Dimension	L	L1	L2	$\theta$
Min.	0.51	-	0.48	0°
Typ.	0.61	-	0.58	
Max.	0.71	0.10	0.81	12°

**Footprint**



◆ Tape&Reel Information:2500pcs/Reel



Package	EDFN5X6-8L
Reel	13"
Device orientation	<p>FEED DIRECTION</p>

Dimension in mm

Dimension	Carrier tape									Reel	
	A0	B0	D0	E	K0	P0	P1	P2	W	R	R1
Typ.	6.4	5.3	1.5	1.8	1.3	4	8	2	12	12.4	330
±	0.2	0.2	0.1	0.1	0.2	0.1	0.1	0.1	0.3	2	2